

**Search Notes**

Application/Control No.

10/815,106

Examiner

Shin-Hon Chen

Applicant(s)/Patent under  
Reexamination

ICHIKAWA ET AL.

Art Unit

2131

**SEARCHED**

Class	Subclass	Date	Examiner
713	158,168	6/8/2007	S.C.
713	169,170	6/8/2007	S.C.
713	156	6/8/2007	S.C.

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
USPAT, PGPUB, DERWENT, JPO, EPO (BRS search- see search history)	6/8/2007	S.C.

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner